



सामग्री प्रबंधन प्रभाग
भारतीय प्रौद्योगिकी संस्थान मुंबई
पवई, मुंबई-400 076, भारत

Materials Management Division
Indian Institute of Technology Bombay
Powai, Mumbai-400 076, India

Phone : (+91-22) 2576 8800,
8801 to 5, 5009, 8848
E-mail : drmm@iitb.ac.in
Website : www.iitb.ac.in

IIT Bombay

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Corrigendum - I

Atomic Force Microscope (AFM)

RFx No. 6100000721 (PR Reference No. 1000016226)

Changes in Technical Specifications

Reference No.	Previous Clause	Changed Clause
2.3	Capable to handle samples sizes > 200mm (dia) and 10mm thick (expandable up to 25 mm). Must come with motorized stages to cover entire sample. Lateral motorized movement of at least 180mm and motorized vertical movement of at least 10mm.	Capable to handle samples sizes greater than or equal to 80 mm (dia) and 10mm thick (expandable up to 25 mm). Must come with manual/motorized stages to cover entire sample
2.4	Include precision encoders for all XYZ axis to provide position accuracy of <2um in XY and <1um in Z	Should be capable of providing position accuracy <2um in XY and <1um in Z, as accessed through the top-optics of the AFM head.
2.5	Must include multi-sample holders and tilting stages	Must include multi-sample holders
2.6	The AFM system must allow software control and automated cantilever approach using the motorized Z stage.	The AFM system must allow software control and automated cantilever approach using the Z stage.
3.15	Non-Contact (true non-contact mode preferable) Tapping Mode	Non-Contact Tapping Mode

for Babantar
Additional Registrar (MM)